

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/622,764	LEE ET AL.
	Examiner	Art Unit
	Tan V. Mai	2193

**SEARCHED**

<b>INTERFERENCE SEARCHED</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>